

MOS INTEGRATED CIRCUIT μ PD16655

240-OUTPUT TFT-LCD GATE DRIVER

The μ PD16655 is a TFT-LCD gate driver equipped with 240-output lines. It can output a high-gate scanning voltage in response to 5 V/3.3 V CMOS level input because it provided with a level-shift circuit as a logic-input circuit. This gate driver is also provided with an output enable (OE) function, so that drivers can be installed at both sides.

FEATURES

- High-output voltage (VDD-VEE = amplitude: 31 V MAX.)
- Shift-direction select function
- Level shift of negative voltage VEE2(level shift range: VDD-VEE2 = 15 V)
- 5 V/3.3 V CMOS level interface
- Output enable function
- As many as 240-output lines
- Slim TCP

ORDERING INFORMATION

Part Number

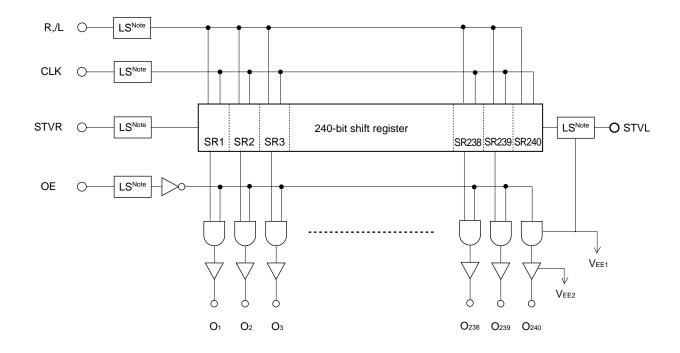
Package

 μ PD16655N-xxx TCP(TAB package)

Remark The TCP's external shape is custom model. To order your TCP's external shape, please contact a NEC salesperson.

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version. Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

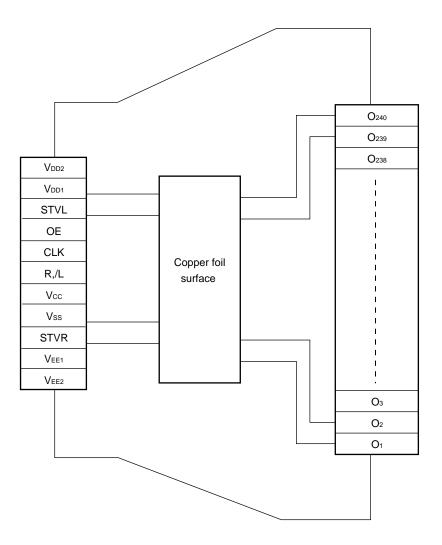
1. BLOCK DIAGRAM



Note LS (level shifter): Shifts 5 V/3.3 V CMOS level and VDD2-VEE1 level.

Remark /xxx indicates active low signal.

2. PIN CONFIGURATION (μ PD16655N-xxx)

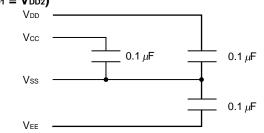


Remark This figure does not specify the TCP package.

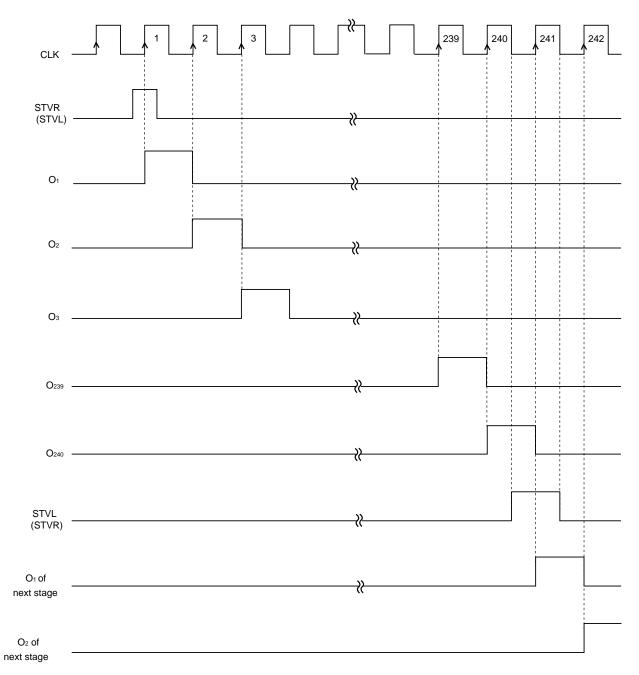
★ 3. PIN FUNCTIONS

SYMBOL	PIN NAME	I/O	DESCRIPTION
O1 to O240	Driver Output		These pins output scan signals that drive the vertical direction (gate lines) of a TFT-LCD. The output signals change in synchronization with the rising edge of shift clock CLK. The driver output amplitude is VDD2 - VEE2.
STVR STVL	Start Pulse Input/Output	Vss/Vcc or Vdd1/Vee1 (input)	This is the input of the internal shift register. The input date is read at the rising edge of shift clock CLK, and scan signals are output from the O_1 through O_{120} pins. The input level is a Vcc/Vss or VDD1 - VEE1 level.
		Vdd1/Vee1 (output)	This pin outputs a start pulse to the μ PD16655 at the next stage when two or more μ PD16655s are connected in cascade. The pulse is output at the falling edge of the 240th clock of shift clock CLK, and is cleared at the falling edge of the 241st clock.
R,/L	Shift Direction Select Input	Vss/Vcc or Vdd1/Vee1	$ \begin{array}{l} R,/L = ``H" \text{ (right shift): } STVR \rightarrow O_1 \rightarrow O_{240} \rightarrow STVL \\ R,/L = ``L" \text{ (left shift): } STVL \rightarrow O_{240} \rightarrow O_1 \rightarrow STVR \end{array} $
CLK	Shift Clock Input	Vss/Vcc	This pin inputs a shift clock to the internal shift register. The shift operation is performed in synchronization with the rising edge of this input.
OE	Output Enable Input	Vss/Vcc	When this pin goes "H", the driver output is fixed to "L". The shift register is not cleared, however. The internal logic operates even when OE = "H". OE is in asynchronization with the clock.
V _{DD1}	Logic Positive Power Supply		10 V to 25 V
V _{DD2}	Driver Positive Power Supply		10 V to 25 V
Vcc	Reference Positive Power Supply		3.0 to 5.5 V Reference voltage to level shifter LS.
Vss	Reference Negative Power Supply		Connect this pin to the ground of the system.
V _{EE1}	Logic Negative Power Supply		-21 V to -3 V
Vee2	Driver Negative Power Supply		-21 V to V _{DD2} - 15 V

- Cautions 1. To prevent latch up, turn on power to Vcc, VEE1-VEE2, VDD1-VDD2, and logic input in this order. Turn off power in the reverse order. These power up/down sequence must be observed also during transition period.
 - Insert a capacitor of about 0.1 μ F between each power line, as shown below, to secure noise margin such as V_{IH} and V_{IL}, because the internal logic operates on a high voltage level. (V_{DD} = V_{DD1} = V_{DD2})



- 3. In an application where the VEE power supply is not shifted, short-circuit VEE2 (driver power) and VEE1 (logic power) outside the TCP. Fix unused pins to the VEE level.
- 4. The level shift range of VEE2 must be VEE1 ≤ VEE2 ≤ VDD 15 V. Note that, in this case, the guaranteed values of the output ON resistance and output fall time slightly change. (VDD = VDD1 = VDD2)



5. TIMING CHART

Caution Do not use a sequence in which the outputs change all at once because such a sequence may cause malfunctioning.

★ 6. ELECTRICAL SPECIFICATION

Absolute Maximum Ratings (T_A = 25°C, V_{SS} = 0 V)

Parameter	Symbol	Ratings	Unit
Logic Positive Supply Voltage	Vdd1	-0.5 to +28	V
Driver Positive Supply Voltage	Vdd2	-0.5 to +28	V
Reference Positive Power Supply Voltage	Vcc	-0.5 to +7	V
Power Supply Voltage	Vdd1-Vee1 Vdd2-Vee2	-0.5 to +33	V
Logic Negative Supply Voltage	Vee1	-23 to +0.5	V
Driver Negative Supply Voltage	VEE2	-23 to +0.5	V
Input Voltage	Vı	VEE1 - 0.5 to VDD1 + 0.5	V
Input Current	h	±10	mA
Output Current	lo	±10	mA
Operating Temperature Range	TA	-30 to +85	°C
Storage Temperature Range	Tstg	-55 to +125	°C

Caution If the absolute maximum rating of even one of the above parameters is exceeded even momentarily, the quality of the product may be degraded. Absolute maximum ratings, therefore, specify the values exceeding which the product may be physically damaged. Be sure to use the product within the range of the absolute maximum ratings.

Recommended Operating Range ($T_A = -30$ to $85^{\circ}C$, $V_{SS} = 0$ V)

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Logic Positive Supply Voltage	Vdd1	10		25	V
Driver Positive Supply Voltage	Vdd2	10		25	V
Logic Negative Supply Voltage	Vee1	-21		-3	V
Driver Negative Supply Voltage	Vee2	-21		Vdd2 - 15	V
Power Supply Voltage	Vdd1-Vee1 Vdd2-Vee2	15		31	V
Reference Positive Power Supply Voltage	Vcc	2.7		5.5	V

Caution Observe the following condition when shifting VEE2 (driver power). Note that, in this case, the guaranteed values of the output ON resistance and output fall time slightly change. $VEE1 \le VEE2 \le VDD - 15 V (VDD1 \text{ or } VDD2)$

ELECTRICAL CHARACTERISTICS (TA = -30 to +85 °C, VDD1 = VDD2 = 22 V, VEE1 = VEE2 = -9 V, Vss = 0 V, Vcc = 2.7 V or 5.5 V)

Parameter	Symbol	Condition	MIN	TYP.	MAX.	Unit
High-Level Input Voltage	Vін		0.7 Vcc		Vdd1	V
Low-Level Input Voltage	VIL		Vee1		0.3 Vcc	V
High-Level Output Voltage	Vон	STVR-STVL, without load	Vdd1 - 0.05		Vdd1	V
Low-Level Output Voltage	Vol	STVR-STVL, without load	Vee1		VEE1 + 0.05	V
High-Level Output Driver Current	Іхон	Driver output, $V_0 = V_{DD2} - 1.0 V$			-2.0	mA
Low-Level Output Driver	Ixol1	Driver output, Vo = VEE2 + 1.0 V	2.0			mA
Current	Ixol2	Driver output, $V_0 = V_{EE2} + 1.0 V$,	1.5			mA
		VEE2 = VDD - 15 V				
LCD Driver Output ON	Ron1	$V_0 = V_{EE2} + 1.0 V, V_{DD2} - 1.0 V$			500	Ω
Resistance	Ron2	Vo = VEE2 + 1.0 V, VDD2 - 1.0 V,			700	Ω
		$V_{EE2} = V_{DD} - 15 V$				
High-Level Output Pulse Current	Ірон	STVR-STVL, Vo = VDD1 - 1.0 V			-2.0	mA
Low-Level Output Pulse Current	IPOL	STVR-STVL, Vo = VEE1 + 1.0 V	2.0			mA
Input Leak Current	١L	Vi = 0 V or 3 V or 5 V			±1	μA
Static Current Dissipation	ldd	VDD1, VDD2 pin, fclk = 31.5 kHz		400	800	μA
	lee	VEE1, VEE2 pin, fCLK = 31.5 kHz		-400	-800	μA
	lcc	Vcc pin, fclк = 31.5 kHz			50	μΑ

★ SWICHING CHARACTERISTICS (TA = -30 to +85 °C, VDD1 = VDD2 = 22 V, VEE1 = VEE2 = -9 V, VSS = 0 V, Vcc = 2.7 V to 5.5 V)

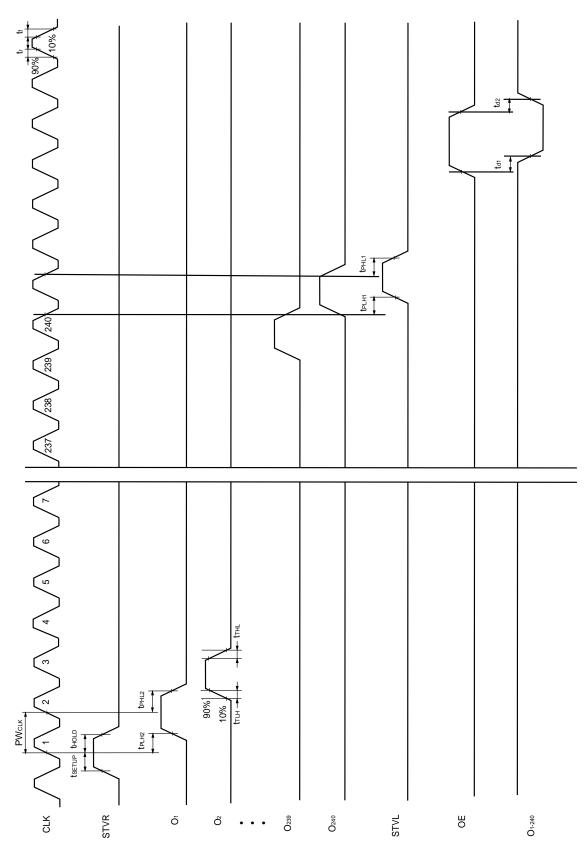
Parameter Symbol		Condition	MIN.	TYP.	MAX.	Unit
Cascade Output Delay Time	tPHL1	C∟ = 20 pF			600	ns
	tPLH1				600	ns
Driver Output Delay Time	tPHL2	CL = 220 pF			700	ns
	tPLH2	$CLK \to Xon$			700	ns
	t _{d1}	$C_L = 220 \text{ pF, OE: } L \to H$			700	ns
	t _{d2}	$C_L = 220 \text{ pF}, \text{ OE}: H \rightarrow L$			700	ns
Output Rise Time	tтьн	CL = 220 pF			300	ns
Output Fall Time	t⊤HL1	CL = 220 pF			300	ns
	tthl2	$C_L = 220 \text{ pF}, V_{EE2} = V_{DD} - 15 \text{ V}$			400	ns
Input Capacitance	Cı	T _A = 25°C			15	pF
Clock Frequency	fclk	In cascade connection	100			kHz

★ TIMING REQUIREMENTS (TA = -30 to 85 °C, VDD1 = VDD2 = 22 V, VEE1 = VEE2 = -9 V, VSS = 0 V, Vcc = 2.7 V to 5.5 V)

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Clock Pulse Width	PWclk		1000			ns
Data Setup Time	tsetup	$STVR(STVL) \uparrow \to CLK \uparrow$	100			ns
Data Hold Time	thold	$CLK \uparrow \to STVR(STVL) \downarrow$	100			ns

Caution Keep the time and fall time of the logic input to $t_r = t_f = 20$ ns (10 to 90 % of the rated values).

★ 7. SWITCHING CHARACTERISTIC WAVEFORM



8. RECOMMENDED SOLDERING CONDITIONS

The following conditions must be met for mounting conditions of the μ PD16655.

For more details, refer to the Semiconductor Device Mounting Technology Manual (C10535E).

Please consult with our sales offices in case other mounting process is used, or in case the mounting is done under different conditions.

μ PD16655N-xxx : TCP(TAB package)

Mounting Condition	Mounting Method	Condition
Thermocompression	Soldering	Heating tool 300 to 350°C, heating for 2 to 3 seconds: pressure 100 g (per solder)
	ACF (Adhesive Conductive Film)	Temporary bonding 70 to 100°C; pressure 3 to 8 kg/cm ² ; time 3 to 5 secs. Real bonding 165 to 180°C; pressure 25 to 45 kg/cm ² , time 30 to 40 secs. (When using the anisotropy conductive film SUMIZAC1003 of Sumitomo Bakelite, Ltd.)

Caution To find out the detailed conditions for mounting the ACF part, please contact the ACF manufacturing company. Be sure to avoid using two or more mounting methods at a time.

- NOTES FOR CMOS DEVICES -

1 PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

② HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

Reference Documents

NEC Semiconductor Device Reliability / Quality Control System (C10983E)

Quality Grades to NEC's Semiconductor Devices (C11531E)

- The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version.
- No part of this document may be copied or reproduced in any form or by any means without the prior written consent of NEC Corporation. NEC Corporation assumes no responsibility for any errors which may appear in this document.
- NEC Corporation does not assume any liability for infringement of patents, copyrights or other intellectual property
 rights of third parties by or arising from use of a device described herein or any other liability arising from use
 of such device. No license, either express, implied or otherwise, is granted under any patents, copyrights or other
 intellectual property rights of NEC Corporation or others.
- Descriptions of circuits, software, and other related information in this document are provided for illustrative
 purposes in semiconductor product operation and application examples. The incorporation of these circuits,
 software, and information in the design of the customer's equipment shall be done under the full responsibility
 of the customer. NEC Corporation assumes no responsibility for any losses incurred by the customer or third
 parties arising from the use of these circuits, software, and information.
- While NEC Corporation has been making continuous effort to enhance the reliability of its semiconductor devices, the possibility of defects cannot be eliminated entirely. To minimize risks of damage or injury to persons or property arising from a defect in an NEC semiconductor device, customers must incorporate sufficient safety measures in its design, such as redundancy, fire-containment, and anti-failure features.
- NEC devices are classified into the following three quality grades:
 "Standard", "Special", and "Specific". The Specific quality grade applies only to devices developed based on a
 customer designated "quality assurance program" for a specific application. The recommended applications of
 a device depend on its quality grade, as indicated below. Customers must check the quality grade of each device
 before using it in a particular application.
 - Standard: Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots
 - Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)
 - Specific: Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems or medical equipment for life support, etc.

The quality grade of NEC devices is "Standard" unless otherwise specified in NEC's Data Sheets or Data Books. If customers intend to use NEC devices for applications other than those specified for Standard quality grade, they should contact an NEC sales representative in advance.